Amendments to the specification:

Please replace paragraph [1008] with the following amended paragraph:

In one embodiment of the present invention, a magnetic lens is provided that can generate a substantially constant amount of average heat power over a pre-selected range of resultant magnetic field strengths. The lens is configured to do this with multiple, asymmetric (different turns) coil sections that can produce a range of desired field strengths, and at the sane-same time, maintain a sufficiently constant temperature signature when the average total power is maintained constant thereby eliminating unreasonable delays in lens operation when the resultant field strength is changed over the operating range of field strengths. The asymmetric lens structure allows for the smaller coil to be made with less relative inductance thereby making it more responsive and amenable for AC signal driving and thus dynamic focusing applications if desired. Thus, a magnetic lens is now provided that can produce a range of magnetic beam-focusing fields strengths, implement dynamic focusing, and not impose unreasonable delay for thermal stabilization between changes in magnetic field strength.

Please replace paragraph [1023] with the following amended paragraph.

In the depicted embodiment, the multi-coil lens assembly 240 comprises a bifurcated primary coil with an inner-disposed, smaller second coil for, among other things, generating a dynamic focusing field component. The multi-coil lens generates a desired magnetic field within a range of operation magnetic field strengths at substantially constant power dissipation. The lens assembly also includes cooling components to assist in maintaining the lens structure thermally stable. Objective lens 240 creates a focusing magnetic field proximal to the sample 202 at the downstream end of the lens assembly for focusing (e.g., de-magnifying) the electron beam just before it reaches the sample. Reflected electrons are then collected through light pipe 249 for providing an image signal of the sample point being scanned.